



EIGHTEENTH ANNUAL

BiTS™

Burn-in & Test Strategies Workshop

March 5 - 8, 2017

Hilton Phoenix / Mesa Hotel
Mesa, Arizona

Archive – Session 2

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Session 2

Jason Mroczkowski
Session Chair

BiTS Workshop 2017 Schedule

Performance Day

Monday March 6 - 1:30 pm

Performance Prediction

"Coaxial Test Socket - Evolution & Optimization"

Frank Zhou - Smiths Connectors

"100G Testing Fixture Design and Verification"

Jackie Luo - Shanghai Zenfocus Semi-Tech

"Inductance Rise Due To Plating"

Gert Hohenwarter - GateWave Northern, Inc.

"Spring probe current-carrying capacity (continuous vs pulse) analysis and improvement"

Yuanjun Shi - TwinSolution Technology Ltd

Coaxial Test Socket - Evolution & Optimization

**Jiachun Zhou (Frank), Dexian Liu
Nhon Huynh, Kevin DeFord
Smiths Interconnect**



**BiTS Workshop
March 5 - 8, 2017**

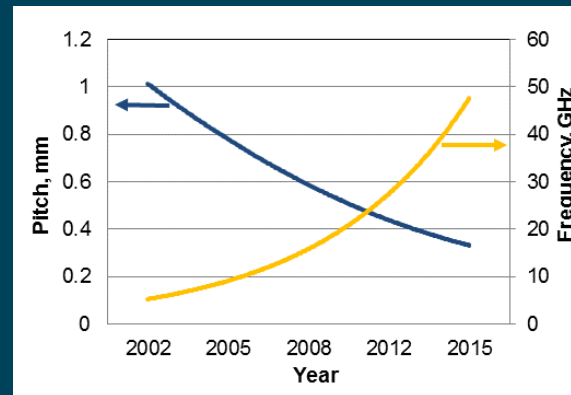


Contents

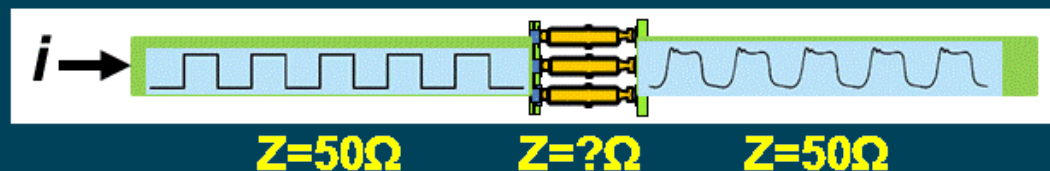
- Why Coaxial Connector Sockets?
- Coaxial Connector Basics
- Major Challenges in Coaxial Socket
- Coaxial Socket Evolution
- Performance Comparison & Continuous Improvements
- Summary

Why Coaxial Connector Sockets?

- Digital world moves to higher frequencies

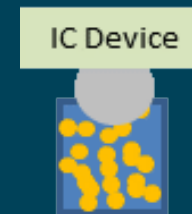


- Interconnects impact signal propagation significantly due to impedance mismatch by connector materials & mechanical structures

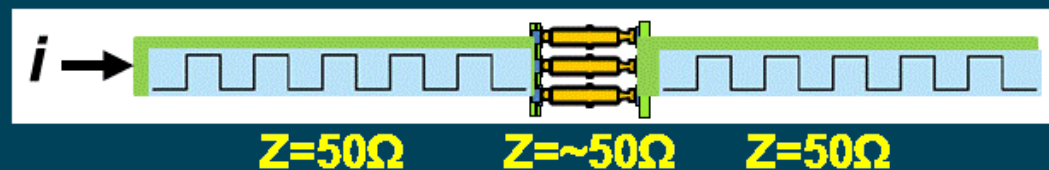


Connectors for High Frequency IC Test

- Shorter connectors, such as conductive elastomer
 - Limited compliance (mostly $<0.20\text{mm}$)
 - High force
 - Manufacturing complexity



- Coaxial structure to control impedance
 - Long spring probe with more compliance ($\sim 0.5\text{mm}$)
 - More reliable contact



Coaxial Structure Basics

- Impedance of typical coaxial cable

$$Z_o = \frac{138}{\sqrt{\epsilon_r}} \log_{10} \frac{D}{d}$$

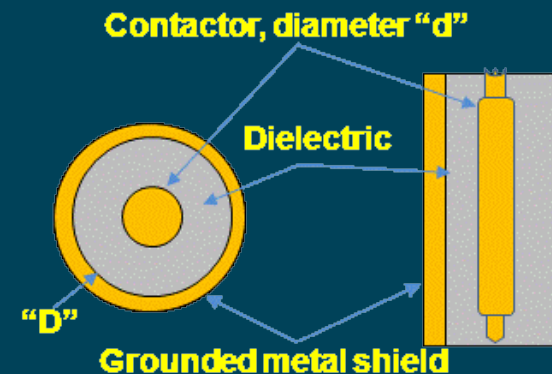
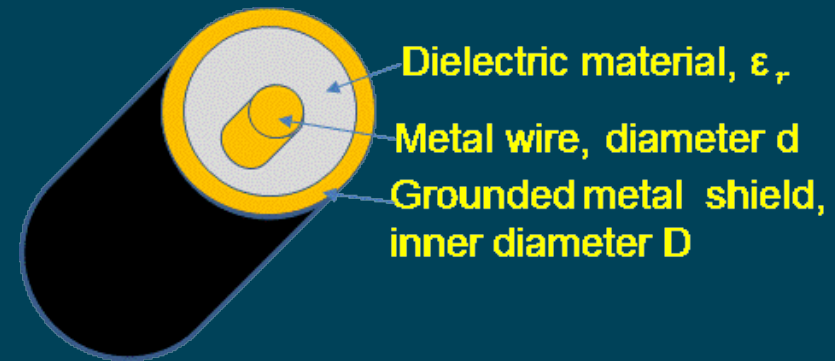
Where:

Z_o : Impedance

D : Inner diameter of grounded metal shield

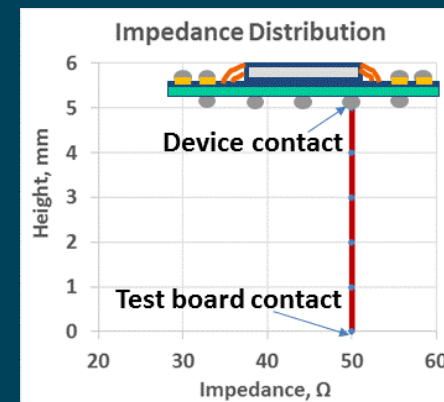
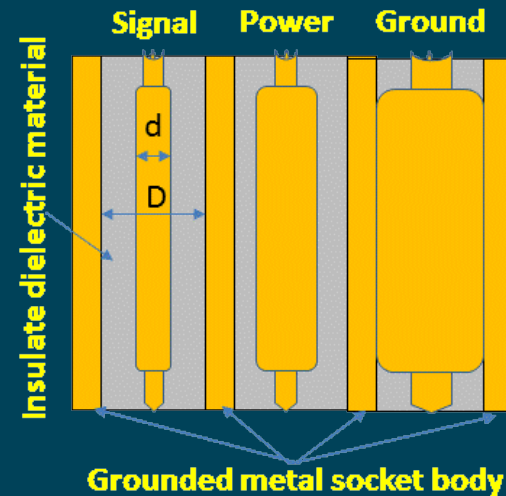
d : Diameter of metal conductor or wire

ϵ_r : Relative dielectric constant of insulator



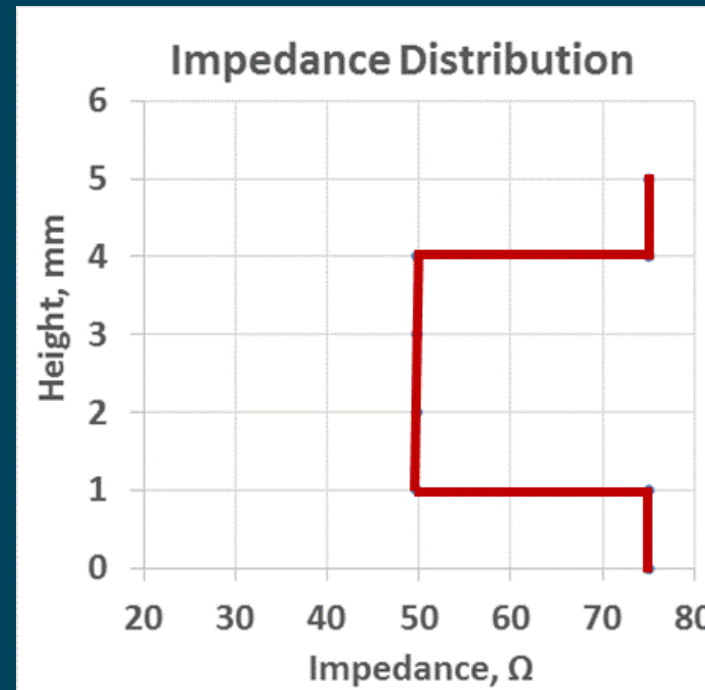
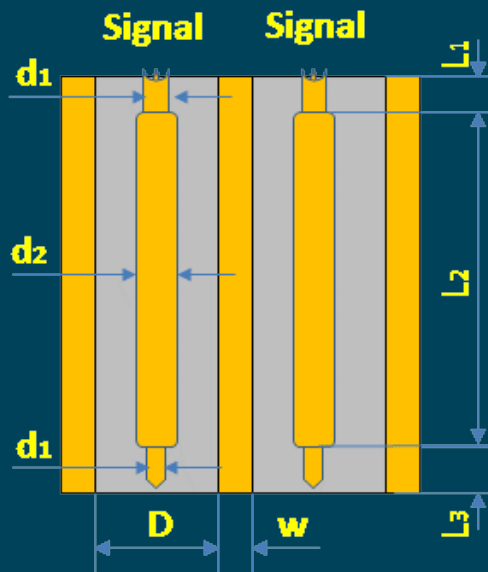
Coaxial Structure Basics

- Coaxial socket structure
 - Probes: signal, power, ground
 - Socket body: metal as conductive shield being grounded
 - Insulate dielectric material in cavities to avoid shortage of signal and power pins to grounded body
 - Diameters of signal pin & its cavity in socket body follows impedance formula
- Coaxial socket idea performance
 - Impedance match to IC package & test board
 - Perfect uniform impedance distribution between contacts from device to board



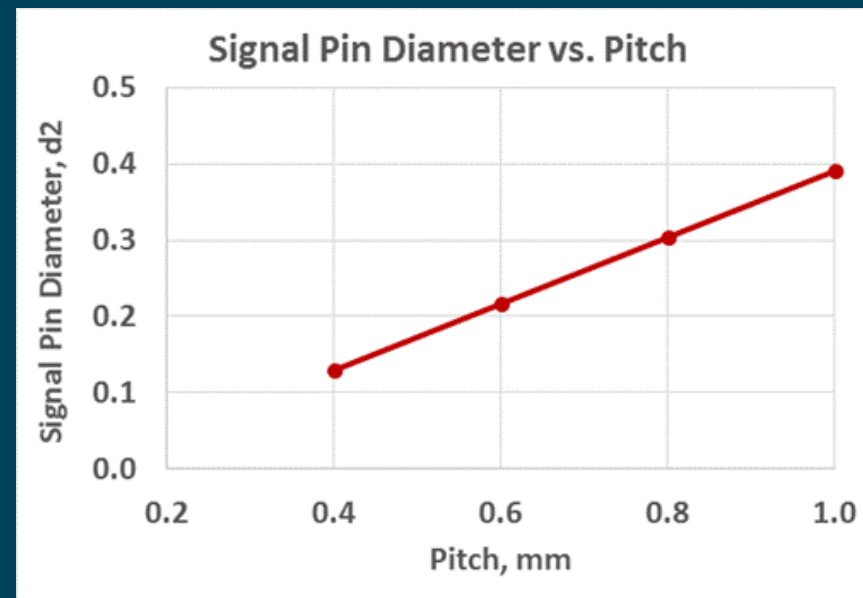
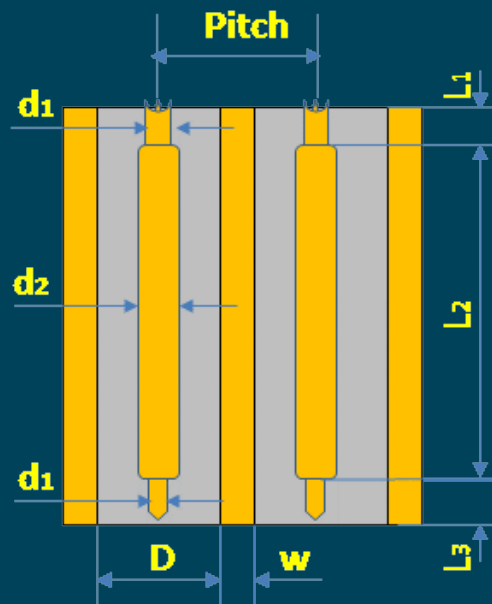
Coaxial Structure Challenges

- Impedance, Z_0 , variations along signal pin
 - Signal probe diameter variation, plunger vs barrel
 - Cavity inner diameter variation due to probe holding feature



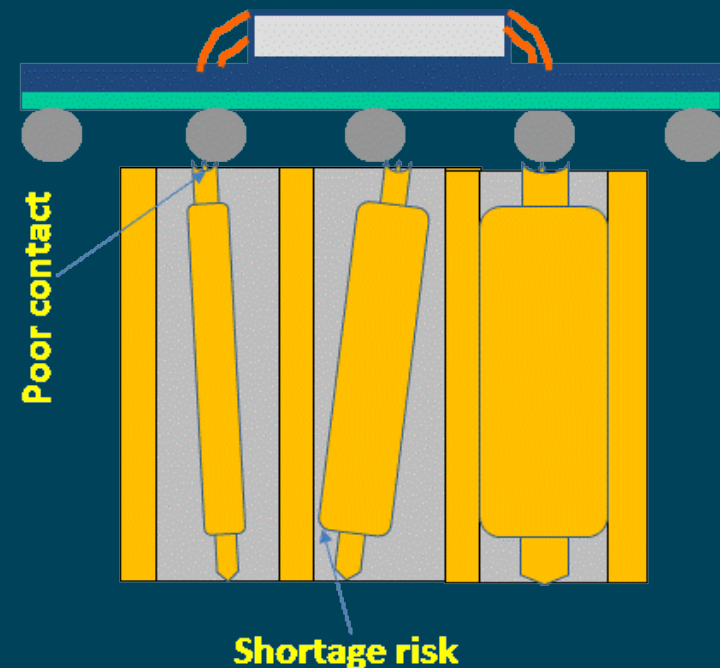
Coaxial Structure Challenges

- Smaller signal pin diameter as pitch is reduced
 - Low force or long probe causes higher contact resistance (C_{res})
 - More difficulties in probe manufacturing
 - More complex signal/power probe retention features in socket



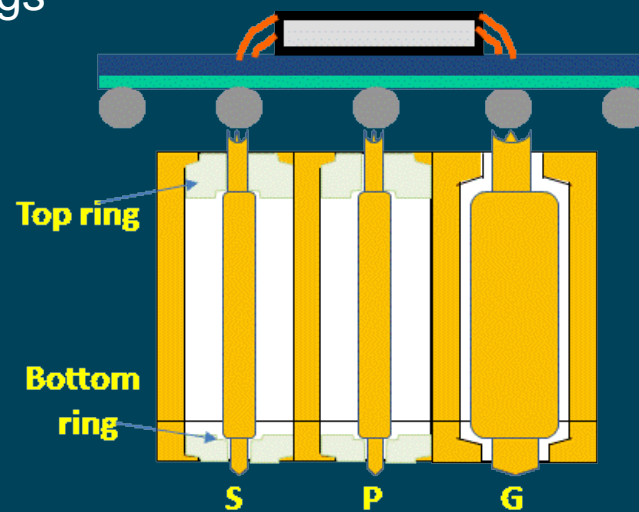
Coaxial Structure Challenges

- More challenges encountered in coaxial socket design
 - Reliable signal & power probe holding features in socket cavities to avoid any shortage to grounded socket metal body
 - Manufacturing and maintenance feasibility of small signal probes in their socket cavities
 - Keeping signal & power probes in the cavity centers to ensure reliable contacts to IC device
 - Ensuring socket body is grounded



Coaxial Socket Evolution: G1

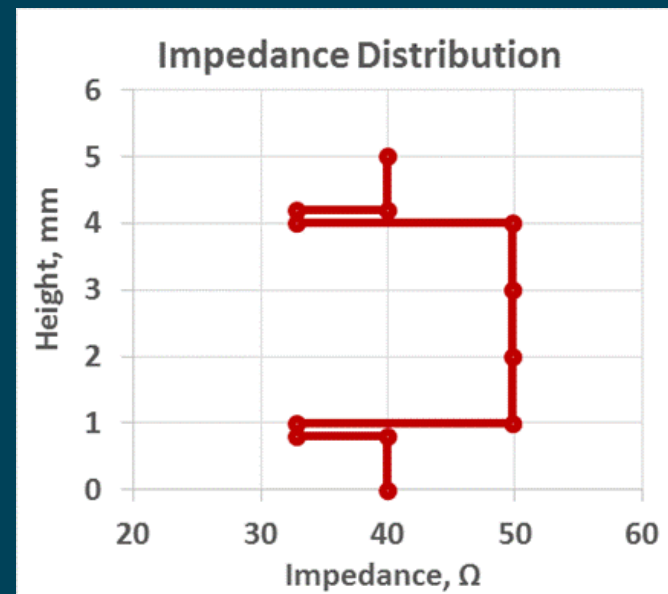
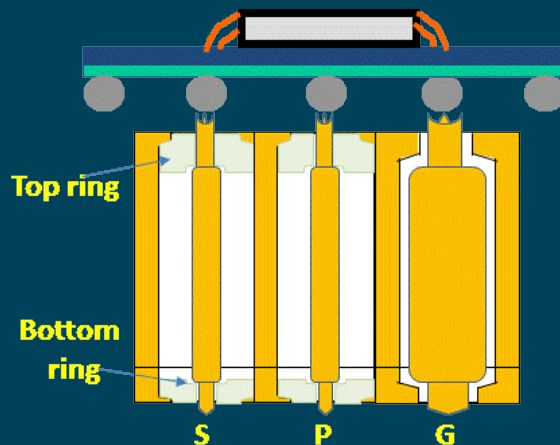
- Coaxial socket G1 basic structure
 - Most section in signal pin with ideal coaxial structure with air as dielectric ($\epsilon_r = 1.0$)
 - Small rings on top/bottom to hold signal & power pins
 - Rings in compressive fitting into cavities (socket body & retainer)
 - Same probes for signal & power
 - Low dielectric constant material with proper mechanical properties for holding rings



Coaxial Test Socket – Evolution & Optimization

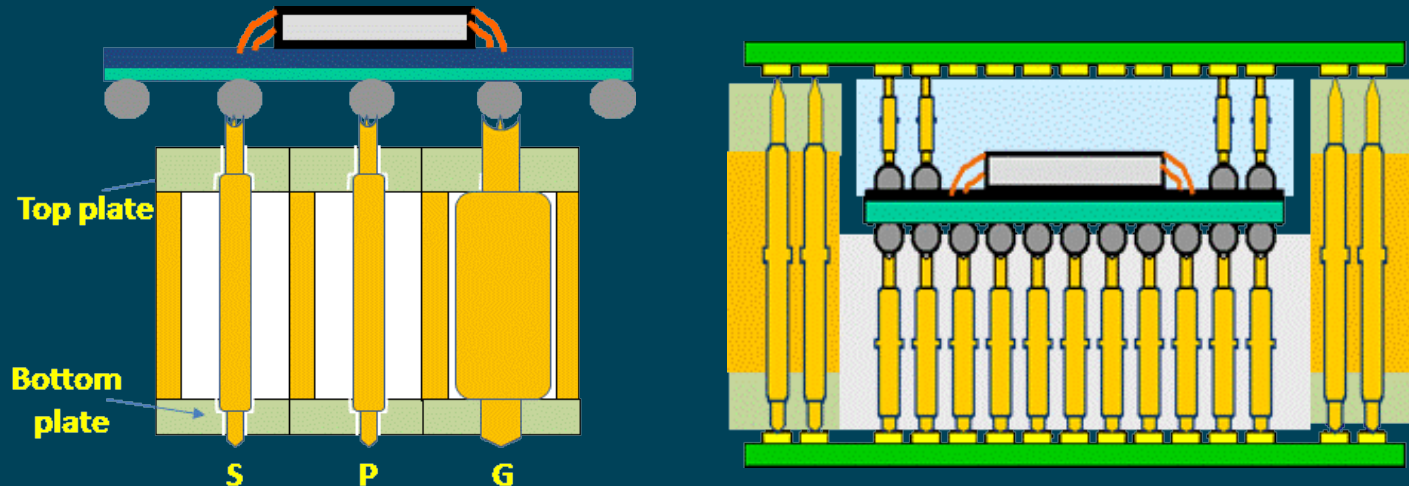
Coaxial Socket Evolution: G1

- Coaxial socket G1 performance & weakness
 - Most section in signal pin, $Z_o = 50\Omega$ impedance
 - Impedance variations in probe holding sections
 - Special process/fixture used in socket assembly/maintenance
 - Ring material impacts on Z_o
 - Two different probes in socket
 - Small rings for better Z_o distribution



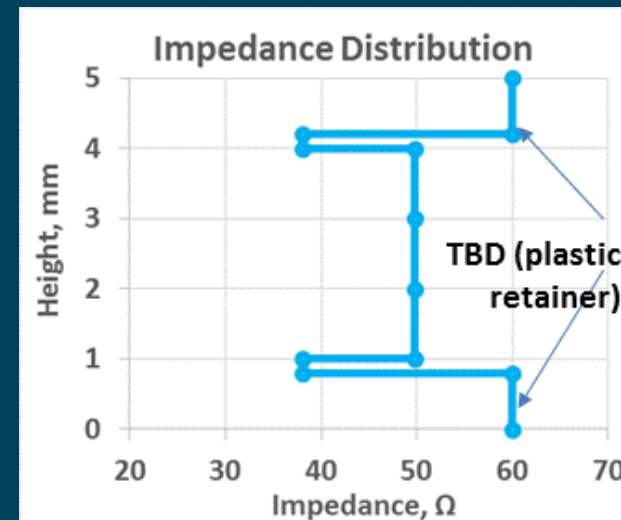
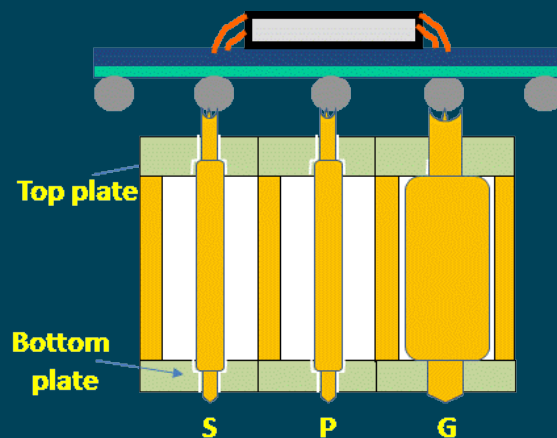
Coaxial Socket Evolution: G2

- Coaxial socket G2 structure
 - Sandwich structures with top/bottom to hold signal/power probe
 - Top/bottom plates by dielectric materials (general socket materials)
 - Feasible in HVM
 - Package on Package (PoP) socket return structure (long electric path) with G2 coaxial structure



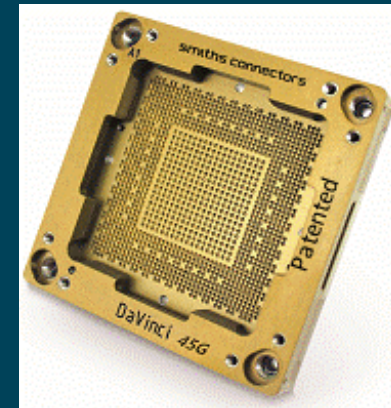
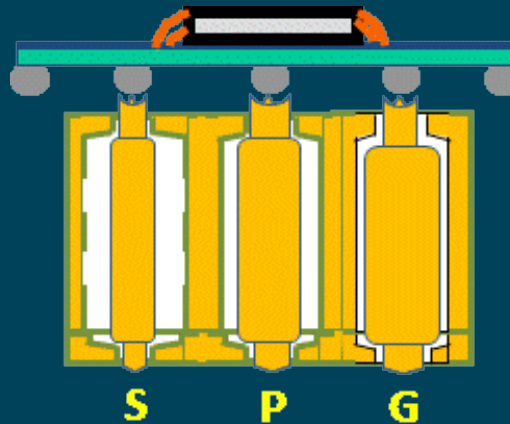
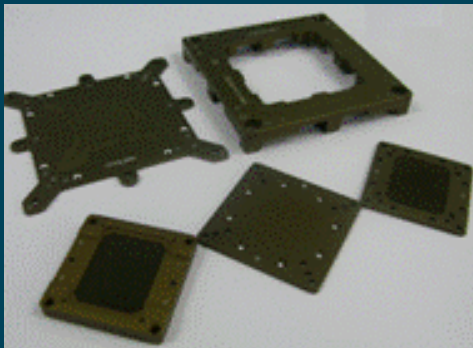
Coaxial Socket Evolution: G2

- Coaxial socket G2 performance, application & weakness
 - Top/bottom plates impacts on Z_0 distributions
 - Top/bottom section impedances calculation same as general sockets
 - Signal/power pins mechanically more stable and reliable contact with devices
 - Concerns of electric shortage



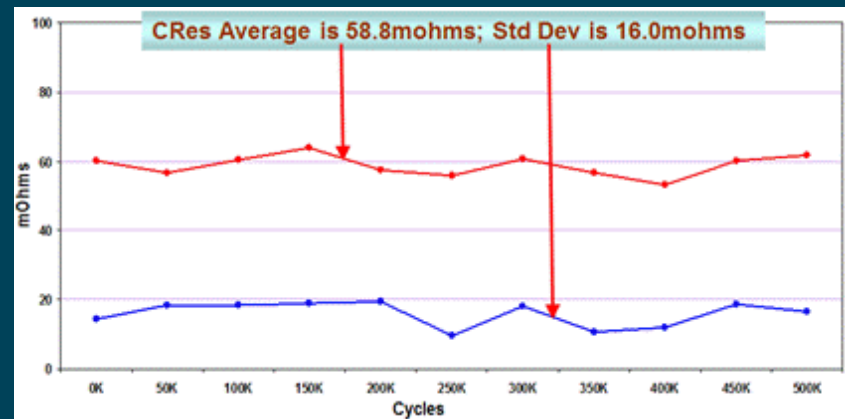
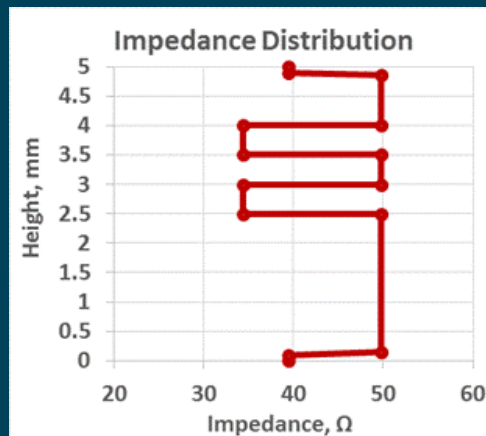
Coaxial Socket Evolution: G3

- Coaxial socket G3 (patented technologies)
 - Surface coated metal as socket body (IM material)
 - Special signal pin holding structures inside socket cavities
 - Same structure of power and ground probe



Coaxial Socket Evolution: G3

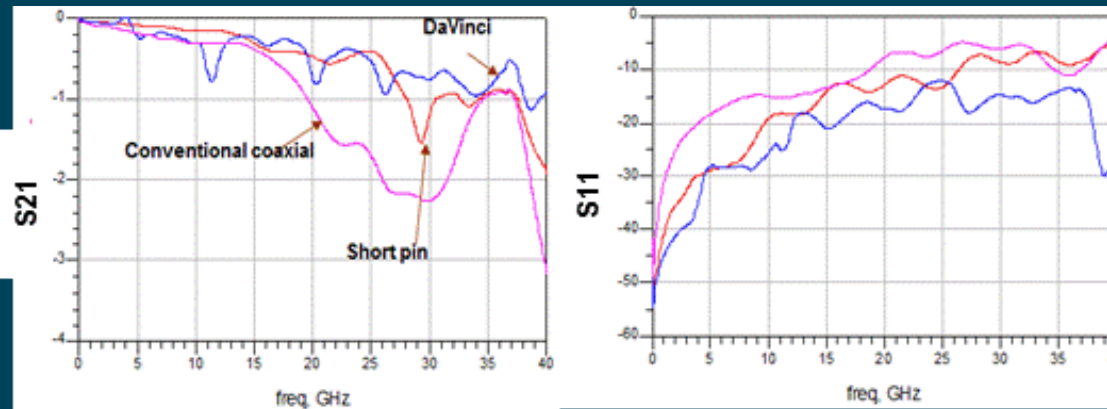
- Coaxial socket G3 performance, application & weakness
 - Avoid electric shortage of signal & power probe to grounded socket
 - Holding feature to ensure signal pin mechanical stability
 - More reliable contacts with device by much better alignment of signal/power probes to device
 - More uniform impedance distributions
 - Signal pins with low Cres
 - More reliable grounding of socket body



Coaxial Socket Evolution: G3

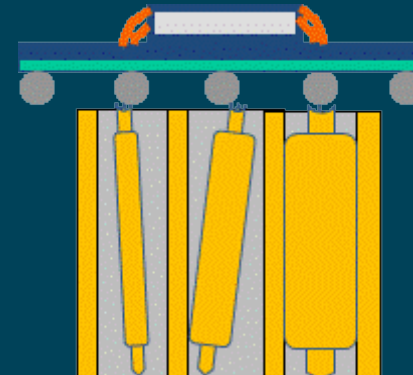
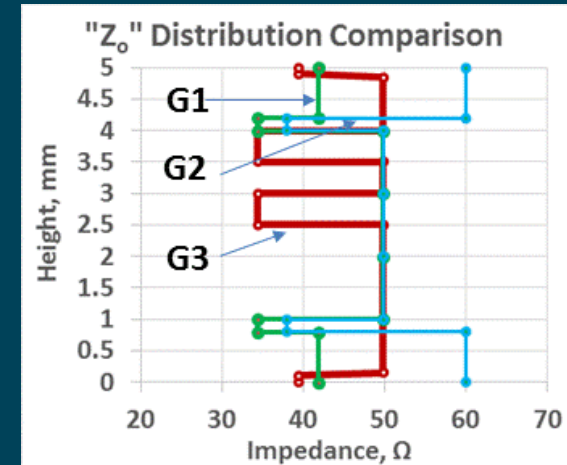
- Coaxial socket G3 performance, application & weakness
 - Improved signal integrity performance as in charts and table below:

	IL, -1.0dB	RL, -10dB
DaVinci	>40GHz	>40GHz
Short pin: 2.15mm length	27GHz	27GHz
Conventional coaxial	19GHz	18GHz



Coaxial Socket Comparison & Continuous Improvements

- Impedance comparison
 - G1 has more uniform impedance
 - G3 is better than G2
- Mechanical stability
 - G3 is better than others in probe stability
 - G2 is better than G1
- Electric shortage
 - G3 socket avoid the electric shortage risk
- Continuous improvements
 - Improve probe holding structure to achieve more uniform impedance distributions
 - Coaxial structure in small pitch



Summary

- Coaxial structure has been successfully applied in test sockets through two decades' development
- Major challenges in coaxial sockets:
 - Keep uniform impedance distributions in complex mechanical structures
 - Proper structure to avoid electric shortage of signal/power probes
 - Retaining signal probe to ensure its mechanical stability
- Sandwich coaxial socket has weakness in RF performance in two holding plates
- Two major improvements in 3rd generation coaxial socket with patented technologies

* Some information originally published in January-February 2017 issue of "Chip Scale Review"